

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.



April 2007

74ACQ374, 74ACTQ374 Quiet Series™ Octal D-Type Flip-Flop with 3-STATE Outputs

Features

- I_{CC} and I_{OZ} reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Improved latch-up immunity
- Buffered positive edge-triggered clock
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24mA
- Faster prop delays than the standard AC/ACT374

General Description

The ACQ/ACTQ374 is a high-speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-STATE outputs for bus-oriented applications. A buffered Clock (CP) and Output Enable $(\overline{\text{OE}})$ are common to all flip-flops.

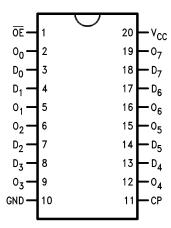
The ACQ/ACTQ374 utilizes FACT Quiet Series™ technology to guarantee quiet output switching and improve dynamic threshold performance. FACT Quiet Series features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Ordering Information

Order Number	Package Number	Package Description
74ACQ374SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACQ374SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACTQ374SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACTQ374SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACTQ374QSC	MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering number.

Connection Diagram

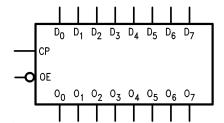


Pin Description

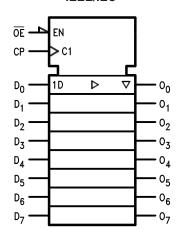
Pin Names	Description
D ₀ –D ₇	Data Inputs
СР	Clock Pulse Input
ŌĒ	3-STATE Output Enable Input
O ₀ -O ₇	3-STATE Outputs

FACT™, Quiet Series™, FACT Quiet Series™, and GTO™ are trademarks of Fairchild Semiconductor Corporation.

Logic Symbol



IEEE/IEC



Functional Description

The ACQ/ACTQ374 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D-type inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable (\overline{OE}) LOW, the contents of the eight flip-flops are available at the outputs. When the \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

Truth Table

	Outputs		
D _n	СР	ŌĒ	On
Н	<i></i>	L	Н
L	~	L	L
Х	Х	Н	Z

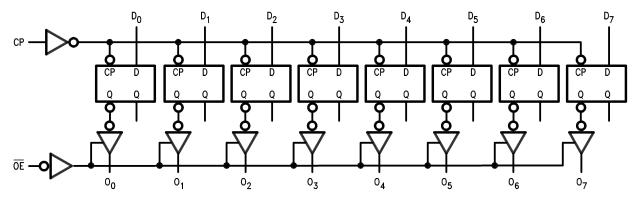
H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

Z = High Impedance

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
V _{CC}	Supply Voltage	-0.5V to +7.0V
I _{IK}	DC Input Diode Current	
	$V_{I} = -0.5V$	–20mA
	$V_{I} = V_{CC} + 0.5V$	+20mA
VI	DC Input Voltage	-0.5V to V _{CC} + 0.5V
I _{OK}	DC Output Diode Current	
	$V_{O} = -0.5V$	–20mA
	$V_{O} = V_{CC} + 0.5V$	+20mA
Vo	DC Output Voltage	-0.5V to V _{CC} + 0.5V
Io	DC Output Source or Sink Current	±50mA
I _{CC} or I _{GND}	DC V _{CC} or Ground Current per Output Pin	±50mA
T _{STG}	Storage Temperature	−65°C to +150°C
	DC Latch-Up Source or Sink Current	±300mA
T _J	Junction Temperature	140°C

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating
V _{CC}	Supply Voltage	
	ACQ	2.0V to 6.0V
	ACTQ	4.5V to 5.5V
V _I	Input Voltage	0V to V _{CC}
Vo	Output Voltage	0V to V _{CC}
T _A	Operating Temperature	-40°C to +85°C
ΔV / Δt	Minimum Input Edge Rate, ACQ Devices:	125mV/ns
	V_{IN} from 30% to 70% of V_{CC} , V_{CC} @ 3.0V, 4.5V, 5.5V	
ΔV / Δt	Minimum Input Edge Rate, ACTQ Devices:	125mV/ns
	V _{IN} from 0.8V to 2.0V, V _{CC} @ 4.5V, 5.5V	

DC Electrical Characteristics for ACQ

				T _A = -	+25°C	$T_A = -40$ °C to +85°C	
Symbol	Parameter	V _{CC} (V)	Conditions	Тур.	G	uaranteed Limits	Units
V _{IH}	Minimum HIGH Level	3.0	$V_{OUT} = 0.1V$ or	1.5	2.1	2.1	V
	Input Voltage	4.5	V _{CC} – 0.1V	2.25	3.15	3.15	
		5.5		2.75	3.85	3.85	
V _{IL}	Maximum LOW Level	3.0	$V_{OUT} = 0.1V$ or	1.5	0.9	0.9	V
	Input Voltage	4.5	V _{CC} – 0.1V	2.25	1.35	1.35	
		5.5		2.75	1.65	1.65	
V _{OH}	Minimum HIGH Level	3.0	$I_{OUT} = -50\mu A$	2.99	2.9	2.9	V
	Output Voltage	4.5		4.49	4.4	4.4	
		5.5		5.49	5.4	5.4	
			$V_{IN} = V_{IL}$ or V_{IH} :				
		3.0	I _{OH} = -12mA		2.56	2.46	
		4.5	I _{OH} = -24mA		3.86	3.76	
		5.5	$I_{OH} = -24 \text{mA}^{(1)}$		4.86	4.76	
V _{OL}	Maximum LOW Level	3.0	I _{OUT} = 50μA	0.002	0.1	0.1	V
	Output Voltage	4.5		0.001	0.1	0.1	
		5.5		0.001	0.1	0.1	
		3.0	I _{OL} = 12mA		0.36	0.44	
		4.5	I _{OL} = 24mA		0.36	0.44	
		5.5	$I_{OL} = 24 \text{mA}^{(1)}$		0.36	0.44	
I _{IN} ⁽³⁾	Maximum Input Leakage Current	5.5	$V_I = V_{CC}$, GND		±0.1	±1.0	μA
I _{OLD}	Minimum Dynamic	5.5	V _{OLD} = 1.65V Max.			75	mA
I _{OHD}	Output Current ⁽²⁾	5.5	V _{OHD} = 3.85V Min.			– 75	mA
I _{CC} ⁽³⁾	Maximum Quiescent Supply Current	5.5	$V_{IN} = V_{CC}$ or GND		4.0	40.0	μA
I _{OZ}	Maximum 3-STATE Leakage Current	5.5	$\begin{aligned} &V_{I}\left(OE\right) = V_{IL}, V_{IH}; \\ &V_{I} = V_{CC}, GND; \\ &V_{O} = V_{CC}, GND \end{aligned}$		±0.25	±2.5	μA
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	Figures 1 & 2 ⁽⁴⁾	1.1	1.5		V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	Figures 1 & 2 ⁽⁴⁾	-0.6	-1.2		V
V_{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	(5)	3.1	3.5		V
V _{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	(5)	1.9	1.5		V

Notes:

- 1. All outputs loaded; thresholds on input associated with output under test.
- 2. Maximum test duration 2.0ms, one output loaded at a time.
- 3. I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC} .
- 4. Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.
- 5. Max number of data inputs (n) switching. (n–1) inputs switching 0V to 5V (ACQ). Input-under-test switching: 5V to threshold (V_{ILD}) , 0V to threshold (V_{IHD}) , f = 1MHz.

DC Electrical Characteristics for ACTQ

				T _A = -	+25°C	$T_A = -40$ °C to +85°C	
Symbol	Parameter	V _{CC} (V)	Conditions	Тур.	G	uaranteed Limits	Units
V _{IH}	Minimum HIGH Level	4.5	$V_{OUT} = 0.1V$ or	1.5	2.0	2.0	V
	Input Voltage	5.5	V _{CC} – 0.1V	1.5	2.0	2.0	1
V _{IL}	Maximum LOW Level	4.5	$V_{OUT} = 0.1V$ or	1.5	0.8	0.8	V
	Input Voltage	5.5	V _{CC} – 0.1V	1.5	0.8	0.8	
V _{OH}	Minimum HIGH Level	4.5	$I_{OUT} = -50\mu A$	4.49	4.4	4.4	V
	Output Voltage	5.5		5.49	5.4	5.4	1
			$V_{IN} = V_{IL}$ or V_{IH} :				
		4.5	$I_{OH} = -24mA$		3.86	3.76	V
		5.5	$I_{OH} = -24 \text{mA}^{(6)}$		4.86	4.76	
V _{OL}	Maximum LOW Level	4.5	$I_{OUT} = 50\mu A$	0.001	0.1	0.1	V
	Output Voltage	5.5		0.001	0.1	0.1	1
			$V_{IN} = V_{IL}$ or V_{IH} :				
		4.5	I _{OL} = 24mA		0.36	0.44	
		5.5	$I_{OL} = 24 \text{mA}^{(6)}$		0.36	0.44	
I _{IN} ⁽³⁾	Maximum Input Leakage Current	5.5	$V_I = V_{CC}$, GND		±0.1	±1.0	μA
I _{OZ}	Maximum 3-STATE Current	5.5	$V_I = V_{IL}, V_{IH};$ $V_O = V_{CC}, GND$		±0.25	±2.5	μA
I _{CCT}	Maximum I _{CC} /Input ⁽³⁾	5.5	$V_I = V_{CC} - 2.1V$	0.6		1.5	mA
I _{OLD}	Minimum Dynamic	5.5	V _{OLD} = 1.65V Max.			75	mA
I _{OHD}	Output Current ⁽⁶⁾		V _{OHD} = 3.85V Min.			– 75	mA
I _{CC} ⁽³⁾	Maximum Quiescent Supply Current	5.5	$V_{IN} = V_{CC}$ or GND		4.0	40.0	μA
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	Figures 1 & 2 ⁽⁸⁾	1.1	1.5		V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	Figures 1 & 2 ⁽⁸⁾	-0.6	-1.2		V
V_{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	(9)	1.9	2.2		V
V_{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	(9)	1.2	0.8		V

Notes:

- 6. All outputs loaded; thresholds on input associated with output under test.
- 7. Maximum test duration 2.0ms, one output loaded at a time.
- 8. Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND
- 9. Max number of data inputs (n) switching. (n–1) inputs switching 0V to 3V (ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}) , 0V to threshold (V_{IHD}) , f = 1MHz.

AC Electrical Characteristics for ACQ

			T,	T _A = +25°C, C _L = 50pF		$T_A = -40$ °C to +85°C, $C_L = 50$ pF		
Symbol	Parameter	V _{CC} (V) ⁽¹⁰⁾	Min.	Тур.	Max.	Min.	Max.	Units
f _{MAX}	Maximum Clock	3.3	75			70		MHz
	Frequency	5.0	90			85		
t _{PLH} , t _{PHL}	Propagation Delay,	3.3	3.0	9.5	13.0	3.0	13.5	ns
	CP to O _n	5.0	2.0	6.5	8.5	2.0	9.0	
t _{PZL} , t _{PZH}	Output Enable Time	3.3	3.0	9.5	13.0	3.0	13.5	ns
		5.0	2.0	6.5	8.5	2.0	9.0	
t _{PHZ} , t _{PLZ}	Output Disable Time	3.3	1.0	9.5	14.5	1.0	15.0	ns
		5.0	1.0	8.0	9.5	1.0	10.0	
toshl, toslh	Output to Output Skew,	3.3		1.0	1.5		1.5	ns
	CP to O _n ⁽¹¹⁾	5.0		0.5	1.0		1.0	

Notes:

- 10. Voltage range 5.0 is 5.0V \pm 0.5V. Voltage range 3.3 is 3.3V \pm 0.3V.
- 11. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements for ACQ

			T _A = +	-25°C, 50pF	$T_A = -40$ °C to +85°C, $C_L = 50$ pF	
Symbol	Parameter	$V_{CC}(V)^{(12)}$	Тур.	Gua	aranteed Minimum	Units
t _S	Setup Time, HIGH or LOW,	3.3	0	3.0	3.0	ns
	D _n to CP	5.0	0	3.0	3.0	
t _H	Hold Time, HIGH or LOW,	3.3	0	1.5	1.5	ns
	D _n to CP	5.0	2.0	1.5	1.5	
t _W	CP Pulse Width, HIGH or LOW	3.3	2.0	4.0	4.0	ns
		5.0	2.0	4.0	4.0	

Note:

12. Voltage range 5.0 is 5.0V \pm 0.5V. Voltage range 3.3 is 3.3V \pm 0.3V

AC Electrical Characteristics for ACTQ

			T _A = +25°C, C _L = 50pF		$T_A = -40$ °C to +85°C, $C_L = 50$ pF			
Symbol	Parameter	V _{CC} (V) ⁽¹³⁾	Min.	Тур.	Max.	Min.	Max.	Units
f _{MAX}	Maximum Clock Frequency	5.0	85			80		MHz
t _{PLH} , t _{PHL}	Propagation Delay, CP to O _n	5.0	2.0	7.0	9.0	2.0	9.5	ns
t _{PZL} , t _{PZH}	Output Enable Time	5.0	2.0	7.5	9.0	2.0	9.5	ns
t _{PHZ} , t _{PLZ}	Output Disable Time	5.0	1.0	8.0	10.0	1.0	10.5	ns
toshl, toshh	Output to Output Skew, CP to O _n ⁽¹⁴⁾	5.0		0.5	1.0		1.0	ns

Notes:

- 13. Voltage range 5.0 is 5.0V ± 0.5V.
- 14. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements for ACTQ

			T _A = +25°C, C _L = 50pF		25°C, $T_A = -40$ °C to +85°C, $C_L = 50$ pF	
Symbol	Parameter	$V_{CC}(V)^{(15)}$	Тур.	Guaranteed Minimum		Units
t _S	Setup Time, HIGH or LOW, D _n to CP	5.0	0	3.0	3.0	ns
t _H	Hold Time, HIGH or LOW, D _n to CP	5.0	0	1.5	1.5	ns
t _H	CP Pulse Width, HIGH or LOW	5.0	2.0	4.0	4.0	ns

Note:

15. Voltage range 5.0 is 5.0V ± 0.5V

Capacitance

Symbol	Parameter	Conditions	Тур.	Units
C _{IN}	Input Capacitance	V _{CC} = OPEN	4.5	pF
C _{PD}	Power Dissipation Capacitance	V _{CC} = 5.0V	42.0	pF

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

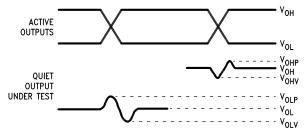
Hewlett Packard Model 8180A Word Generator

PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50pF, 500Ω .
- Deskew the HFS generator so that no two channels have greater than 150ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
- 3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- Set the HFS generator to toggle all but one output at a frequency of 1MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
- Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



Notes:

- 16. V_{OHV} and V_{OLP} are measured with respect to ground reference
- 17. Input pulses have the following characteristics: f = 1MHz, $t_r = 3ns$, $t_f = 3ns$, skew < 150ps.

Figure 1. Quiet Output Noise Voltage Waveforms

V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV}:

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the worst case transition for active and enable.
 Measure V_{OHP} and V_{OHV} on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate or steps out a min of 2ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{IL} D.
- Next decrease the input HIGH voltage level, V_{IH}, until the output begins to oscillate or steps out a min of 2ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

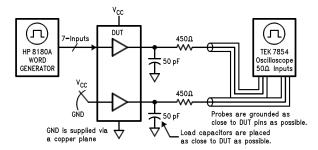
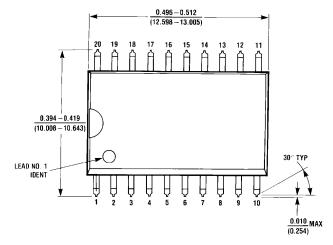
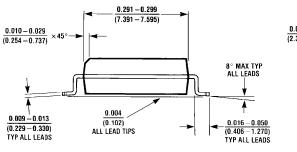


Figure 2. Simultaneous Switching Test Circuit

Physical Dimensions

Dimensions are in inches (millimeters) unless otherwise noted.





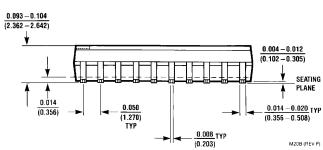
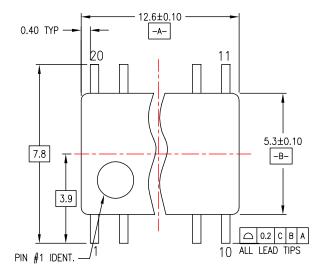
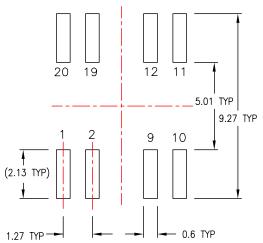


Figure 3. 20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Package Number M20B

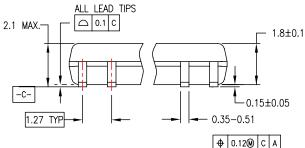
Physical Dimensions (Continued)

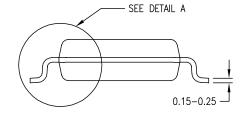
Dimensions are in millimeters unless otherwise noted.





LAND PATTERN RECOMMENDATION

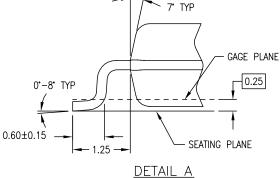




DIMENSIONS ARE IN MILLIMETERS

NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998.
 B. DIMENSIONS ARE IN MILLIMETERS.
 C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.



M20DREVC

Figure 4. 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D

Physical Dimensions (Continued) Dimensions are in millimeters unless otherwise noted. (0.35) (1.7) [.014] [.067] 20 8,66 ○ 0.10 M A-B [.341] 4X (1.34) [.053] (7.1) (3.7) [.280] [.146] 6 [،236] 3.9 [.154] (0.635)1 0.10 M A-B (0.317)[.025] △ 0.20 M C [.013] 2X N/2 TIPS 0.28 0.2 - .011 - .008 PIN 1 [.025] **LAND PATTERN TOP VIEW RECOMMENDATION** 1.357±0.127 DETAIL A [.053±.005] -10°±5 1.6±0.05 [.063±.002] **END VIEW SIDE VIEW** 0.25-0.5 -0.25-0.5 [.01-.02] [.01-0.02] R0.09 Min-GAGE NOTES : .254 **PLANE** [0.010] A. THIS PACKAGE CONFORMS TO JEDEC M0-137 VARIATION AD B. PRIMARY DIMENSIONS IN MILLIMETERS SEATING REFERENCE DIMENSIONS IN INCHES [0.020-0.0295] **PLANE** C. DRAWING CONFORMS TO ASME Y14.5M-1994 —(1)— [0.039] D. DIMENSIONS ARE EXCLUSIVE OF BURRS, **DETAIL A** MOLD FLASH, AND TIE BAR EXTRUSIONS.

Figure 5. 20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide Package Number MQA20

MQA20REVA





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PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
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